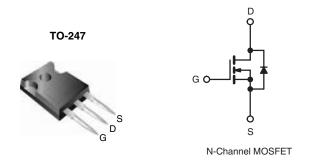


Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	500	500		
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.23		
Q _g (Max.) (nC)	120			
Q _{gs} (nC)	32			
Q _{gd} (nC)	52			
Configuration	Single			



FEATURES

• Low Gate Charge Qq Results in Simple Drive Requirement



 Improved Gate, Avalanche and Dynamic dV/dt RoHS Ruggedness

- Fully Characterized Capacitance and Avalanche Voltage and Current
- Lead (Pb)-free Available

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptable Power Supply
- High Speed Power Switching

TYPICAL SMPS TOPOLOGIES

- Full Bridge Converters
- Power Factor Correction Boost

ORDERING INFORMATION		
Package	TO-247	
Lead (Pb)-free	IRP22N50APbF	
	SiHFP22N50A-E3	
SnPb	IRP22N50A	
	SiHFP22N50A	

ABSOLUTE MAXIMUM RATINGS T	_C = 25 °C, unless otherw	rise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V_{DS}	500	V	
Gate-Source Voltage	V_{GS}	± 30	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \		
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25 ^{\circ}C$ $T_{C} = 100 ^{\circ}C$		22	А	
	$T_C = 100 ^{\circ}C$	I _D	14		
Pulsed Drain Current ^a	I _{DM}	88			
Linear Derating Factor		2.2	W/°C		
Single Pulse Avalanche Energy ^b	E _{AS}	1180	mJ		
Repetitive Avalanche Current ^a	I _{AR}	22	Α		
Repetitive Avalanche Energy ^a	E _{AR}	28	mJ		
Maximum Power Dissipation	T _C = 25 °C	P_{D}	277	W	
Peak Diode Recovery dV/dtc	dV/dt	4.8	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s	-	300 ^d		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	6-32 OF IVI3 SCIEW		1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Starting T_J = 25 °C, L = 4.87 mH, R_G = 25 $\Omega,\,I_{AS}$ = 22 A (see fig. 12).
- c. $I_{SD} \leq 22$ A, $dI/dt \leq 190$ A/µs, $V_{DD} \leq V_{DS}, \, T_{J} \leq 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFP22N50A, SiHFP22N50A

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THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	40	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.45	

PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT
Static		1					
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		500	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	i	0.55	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	V _{GS} , I _D = 250 μA	2.0	-	4.0	٧
Gate-Source Leakage	I _{GSS}	\	V _{GS} = ± 30 V		-	± 100	nA
		V _{DS} =	V _{DS} = 500 V, V _{GS} = 0 V		-	25	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 400 V	V _{GS} = 0 V, T _J = 125 °C	i	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 13 A ^b	ı	-	0.23	Ω
Forward Transconductance	9fs	V _{DS} =	50 V, I _D = 13 A ^b	12	-	-	S
Dynamic		1				•	
Input Capacitance	C _{iss}		$V_{GS} = 0 \text{ V}, \\ V_{DS} = 25 \text{ V},$		3450	-	-
Output Capacitance	C _{oss}	,			513	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		i	27	-	
Output Capacitance	C _{oss}	V _{GS} = 0 V	V _{DS} = 1.0 V, f = 1.0 MHz		4935		pF
			V _{DS} = 400 V, f = 1.0 MHz		137		
Effective Output Capacitance	C _{oss} eff.		V _{DS} = 0 V to 400 V ^c		264		
Total Gate Charge	Qg			-	-	120	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 22 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b	-	-	32	
Gate-Drain Charge	Q_{gd}		ooo ng. o ana ro	-	-	52	
Turn-On Delay Time	t _{d(on)}			-	26	-	
Rise Time	t _r	Von -	V 250 V I 20 A		94	-	1
Turn-Off Delay Time	t _{d(off)}	$V_{DD} = 250 \text{ V, } I_D = 22 \text{ A,}$ $R_G = 4.3 \ \Omega, \ R_D = 11 \ \Omega, \text{ see fig. } 10^b$		-	47	-	- ns -
Fall Time	t _f			-	47	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	22	A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	88	_ ^
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 22\text{A}, V_{GS} = 0 V^b$		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 22 A, dI/dt = 100 A/μs ^b		-	570	850	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	6.1	9.2	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.
- c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80 % V_{DS} .





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

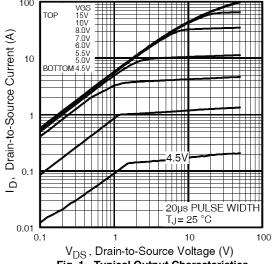


Fig. 1 - Typical Output Characteristics

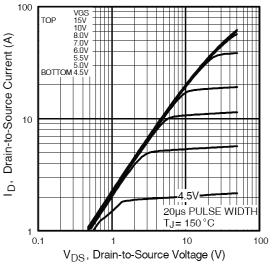


Fig. 2 - Typical Output Characteristics

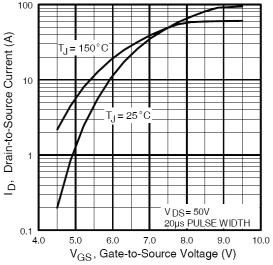


Fig. 3 - Typical Transfer Characteristics

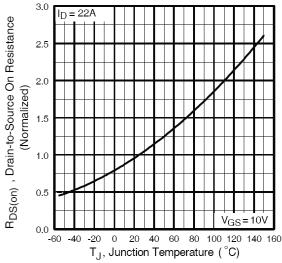


Fig. 4 - Normalized On-Resistance vs. Temperature

IRFP22N50A, SiHFP22N50A

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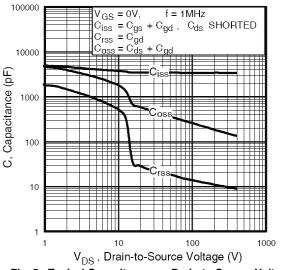


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

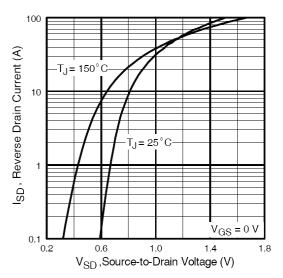


Fig. 7 - Typical Source-Drain Diode Forward Voltage

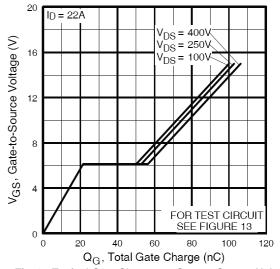


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

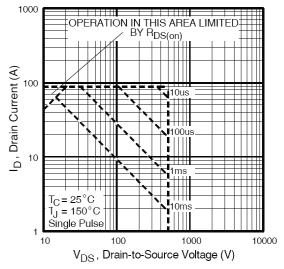
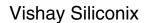


Fig. 8 - Maximum Safe Operating Area





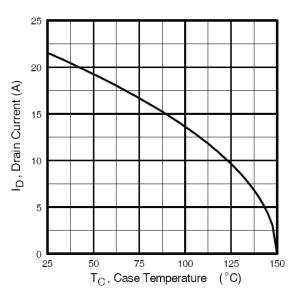


Fig. 9 - Maximum Drain Current vs. Case Temperature

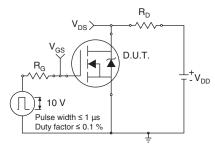


Fig. 10a - Switching Time Test Circuit

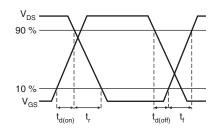


Fig. 10b - Switching Time Waveforms

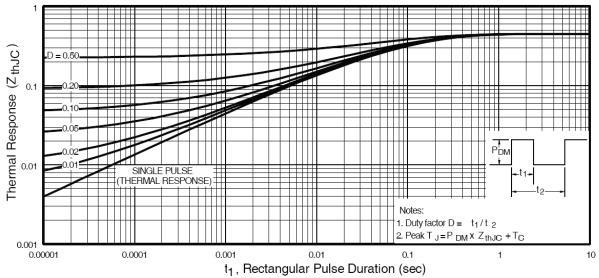


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

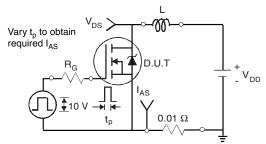


Fig. 12a - Unclamped Inductive Test Circuit

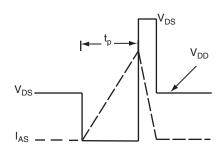


Fig. 12b - Unclamped Inductive Waveforms

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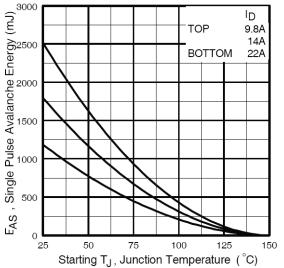


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

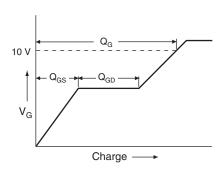


Fig. 13a - Basic Gate Charge Waveform

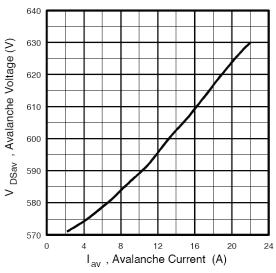


Fig. 12d - Typical Drain-to-Source Voltage vs.
Avalanche Current

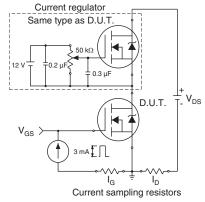
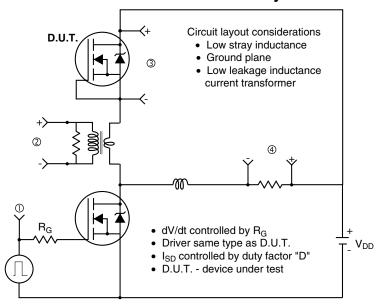
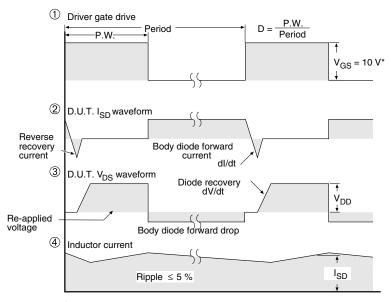


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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